



Tomasz Brozek received M.S. EE degree and Ph.D. degree in Physics from Institute of Semiconductors, Ukrainian Academy of Sciences in Kiev. He started his career as an Assistant Professor and lead research projects in physics and technology of MOS devices at Warsaw University of Technology, Poland and at University of California, Los Angeles. Dr. Brozek has been with PDF Solutions since 2000 and currently holds an Engagement Director and Senior Technical Fellow position, with extensive experience in technology development, FEOL/MOL/BEOL integration, transistor and process characterization, reliability and yield improvement. He has served as Engagement Manager and led several successful PDF yield ramp projects in the past. He has been working on projects with

advanced CMOS (down to 5nm node), NVM FLASH, MRAM, PCM, NAND, DRAM, MOS Image Sensors. Before joining PDF Solutions he was with Motorola, working on device characterization, charging damage, process assessment, and reliability support for technology development and transfer of Logic, BiCMOS, and eFlash technologies. Dr. Brozek has published almost 100 technical papers and conference presentation, and holds numerous patents. He is also chairing a Technical Committee for Semiconductor Manufacturing of IEEE Electron Device Society.